

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-15
CB Certificate No.: 50600328 ITL

Schedule Number: IECQ-L ULTW 16.0003-15-S Rev No.: 1 Revision Date: 2024/08/07 Page 1 of 1

Appendix-1 (50600328 ITL) Schedule of Scope to Certificate of Approval

| Description test | Standard |
|---|----------------------------|
| Optical Microscope (OM) | T-OMI-3 |
| High Temperature Operation Life test (HTOL) | IEC 60068-2-1, JESD22-A108 |
| Low Temperature Operation Life test (LTOL) | IEC 60068-2-1, JESD22-A108 |
| Bias Life test (BLT) | JESD22-A108 |
| Highly Accelerated Stress test (HAST) | JESD22-A110 |
| Temperature and Humidity with Bias test (THB) | JESD22-A101 |

Technical Reviewer of DQS: Paul Torg Date: 8/7/2024

